INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Multiple sheets used when necessary) SHEET 1 OF 1		Application No.	10/820,381
		Filing Date	April 8, 2004
		First Named Inventor	Plasterer, et al.
		Art Unit	2819
		Examiner	Anh Q. Tran
		Attorney Docket No.	DATUMTE.018A

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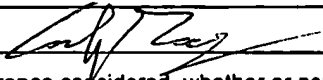| Examiner Initials	Cite No.	Document Number Number - Kind Code (if known) Example: 1,234,567 B1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear
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NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T[1]
A.T		BARRIE GILBERT, The Multi-tanh Principle: A Tutorial Overview, IEEE Journal of Solid-State Circuits, Vol. 33, No. 1, January 1998, Institute of Electrical and Electronics Engineers, Inc., pp. 2-17.	
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Examiner Signature		Date Considered	3/13/06

*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

T[1] - Place a check mark in this area when an English language Translation is attached.